

Quantitative Electron Microscopy

Quantitative Electron Microscopy becomes an essential tool to extract a faint feature or to detect small change of the structure. Quantitative Electron Microscopy has a long history, but it becomes recently doable with emergence of a stable microscope and/or a high-performance PC. In the occasion of EMC2012, we have arranged a series of workshops, where we present some of our software for Quantitative Electron Microscopy. You may note that most of the presentations are given by the researchers, who developed the procedures for Quantitative Electron Microscopy. Our workshop schedule is as follows:

Monday, 14:45-15:30

- Quantitative HAADF analysis (qHAADF) by Sergio I Molina (Univ. of Cadiz)
- Quantitative Electron Diffraction (QED) by Christoph Koch (Ulm University)

Tuesday, 11:00-11:45

Exit Wave Reconstruction (IWFR, FTSR, QPt) by Kazuo Ishizuka (HREM Res.)

Wednesday, 11:00-11:45

- Peak-Pairs Analysis (PPA) by Pedro L. Galindo (Univ. of Cadiz)
- Multivariate Statistical Analysis (MSA) by Masashi Watanabe (Lehigh University)

Thursday, 11:00-11:45

 Geometrical Phase Analysis (GPA) and Dark-Field Hologoraphy (HoloDark) by Martin Hytch (CEMES-CNRS)

If you are not familiar with the titles of the presentations, please visit our web site (www.hremresearch.com) and get more information before attending the workshop.

About HREM Research Inc.

Funded in 2001HREM, Research becomes a leading company developing versatile software for Quantitative Electron Microscopy. Our flagship software is FFT-Multislice HRTEM/STEM Image Simulation Package. We also provide a collection of DigitalMicrograph plug-ins, which includes Exit Wave Reconstruction, STEM-HAADSF and EELS Deconvolution, Strain Mapping, Noise Filters, Multivariate SI Data Analysis, Rocking Beam Electron Diffraction Data Acquisition and more.

